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(12) **United States Design Patent**
**Parrish et al.**

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(54) **DUAL MEASURING LEVEL**

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(**) Term: **15 Years**

(21) Appl. No.: **29/723,652**

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(52) **U.S. Cl.**
USPC ............................................................ **D10/69**

(58) **Field of Classification Search**
USPC ............................ D10/69, 74; D19/133, 156
CPC .......... G01C 5/00; G01C 15/02; G06N 20/00; G01B 3/566; B43L 7/02; B43L 7/027
See application file for complete search history.

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(57) **CLAIM**

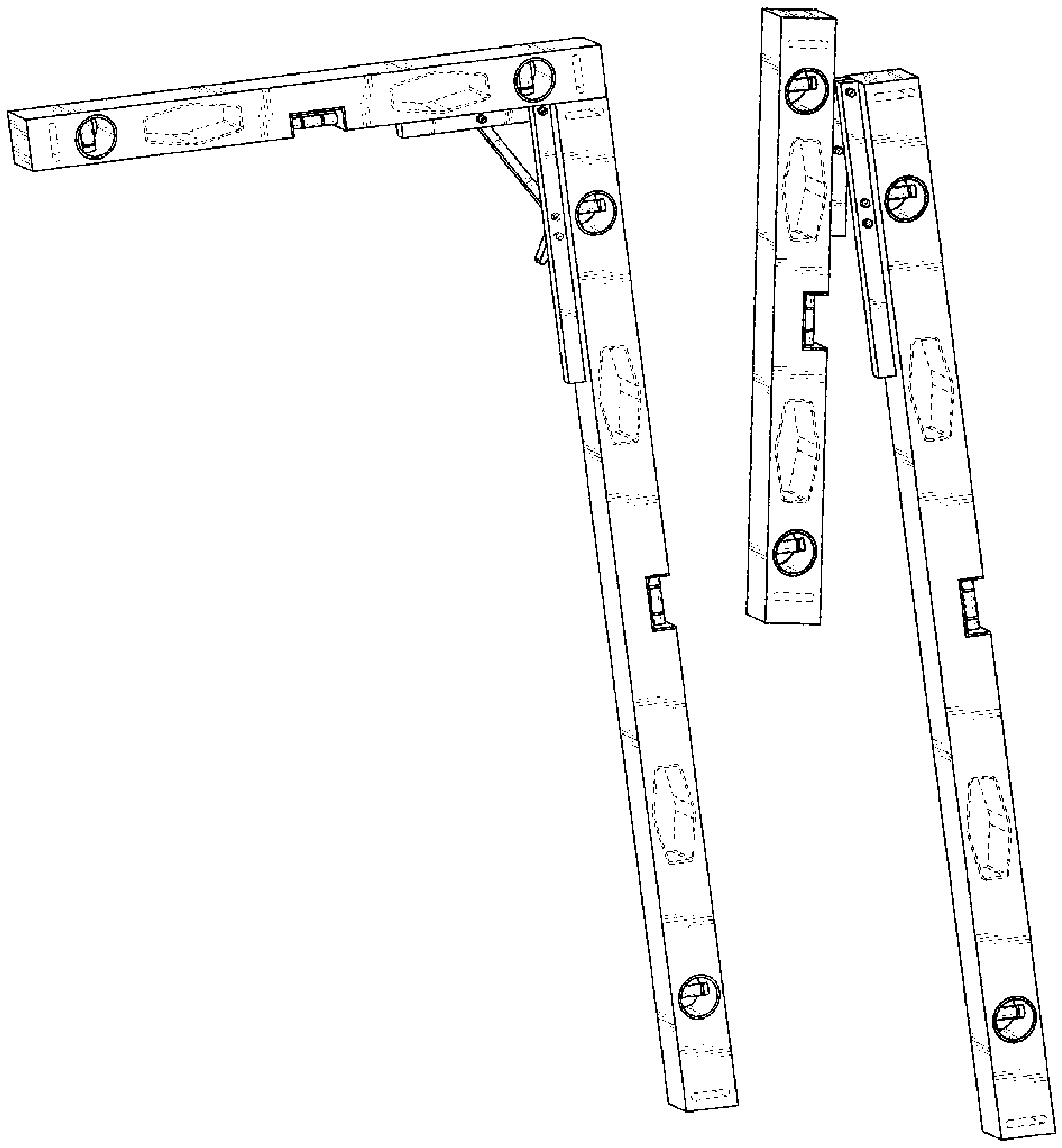
The ornamental design for a dual measuring level, as shown and described.

**DESCRIPTION**

FIG. **1** is an isometric view of a dual measuring level showing our new design, in an open configuration;
FIG. **2** is an isometric view thereof, in a closed configuration;
FIG. **3** is a front elevational view thereof, in an open configuration;
FIG. **4** is a rear elevational view thereof;
FIG. **5** is a left side elevational view thereof;
FIG. **6** is a right elevational view thereof;
FIG. **7** is a top plan view thereof; and,
FIG. **8** is a bottom plan view thereof.

The broken lines represent portions of the dual measuring level that forms no part of the claimed design.

**1 Claim, 8 Drawing Sheets**



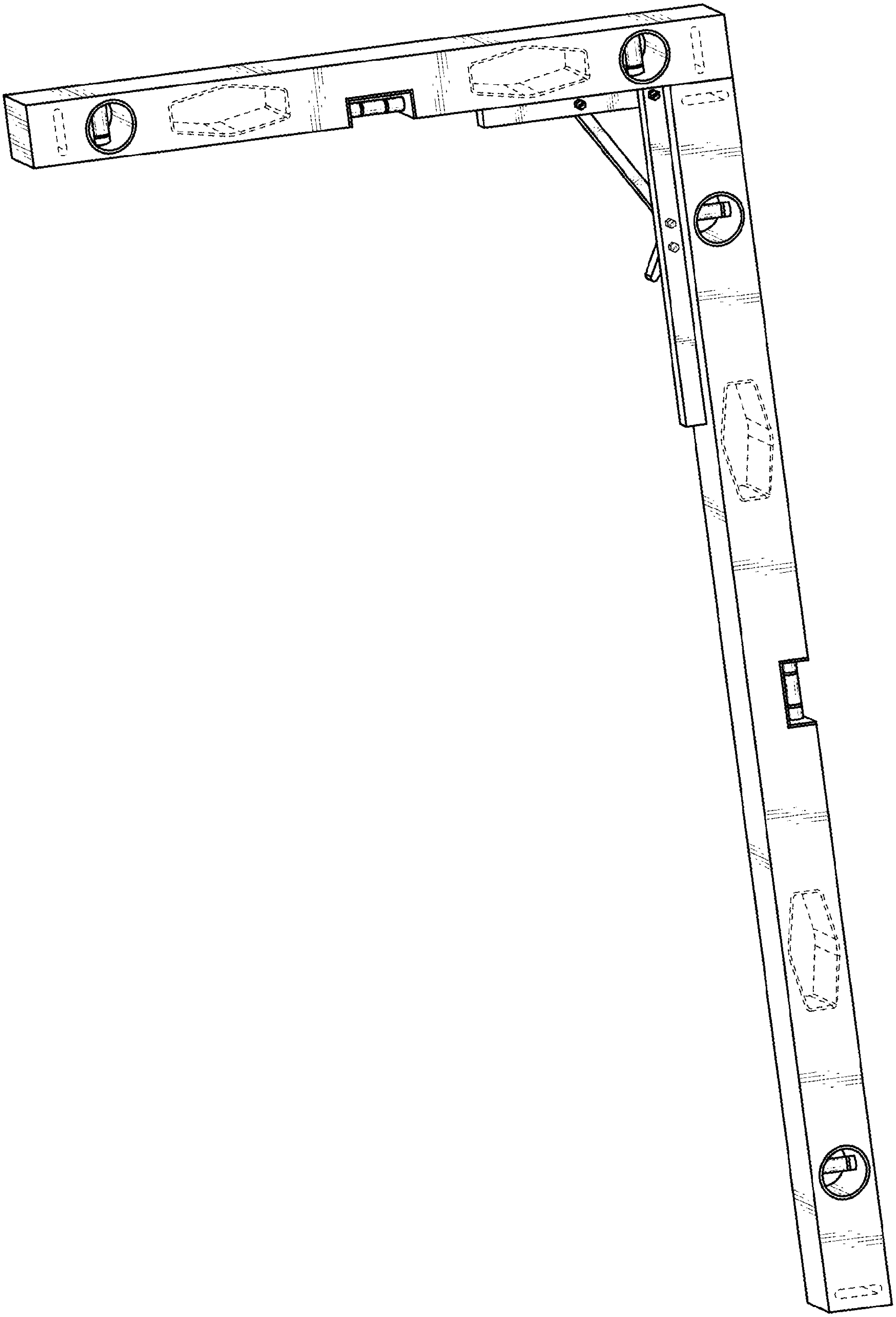


FIG. 1

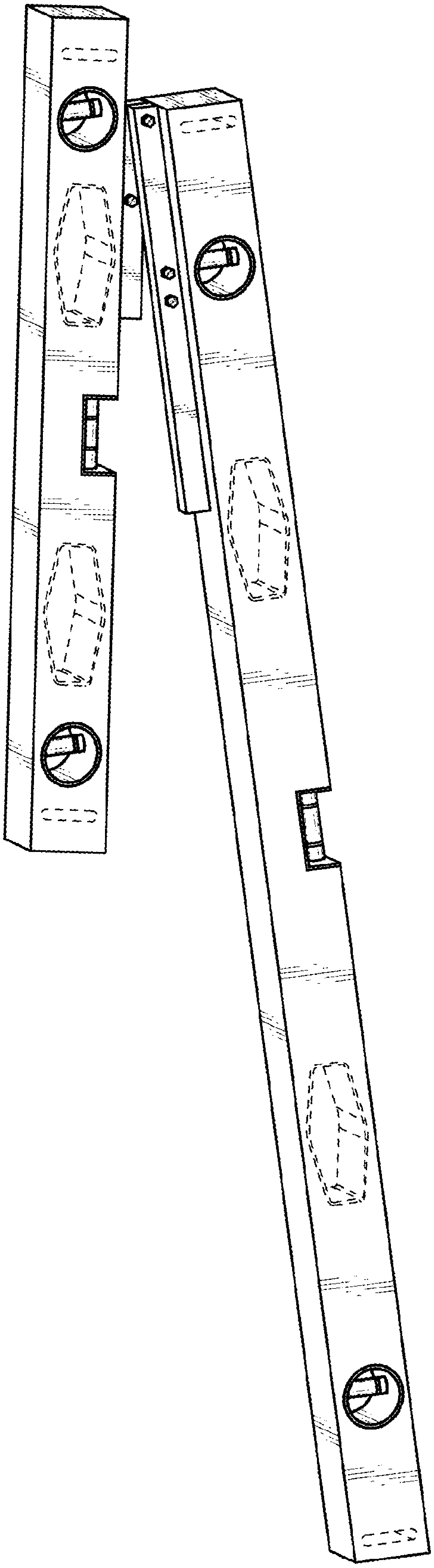


FIG. 2

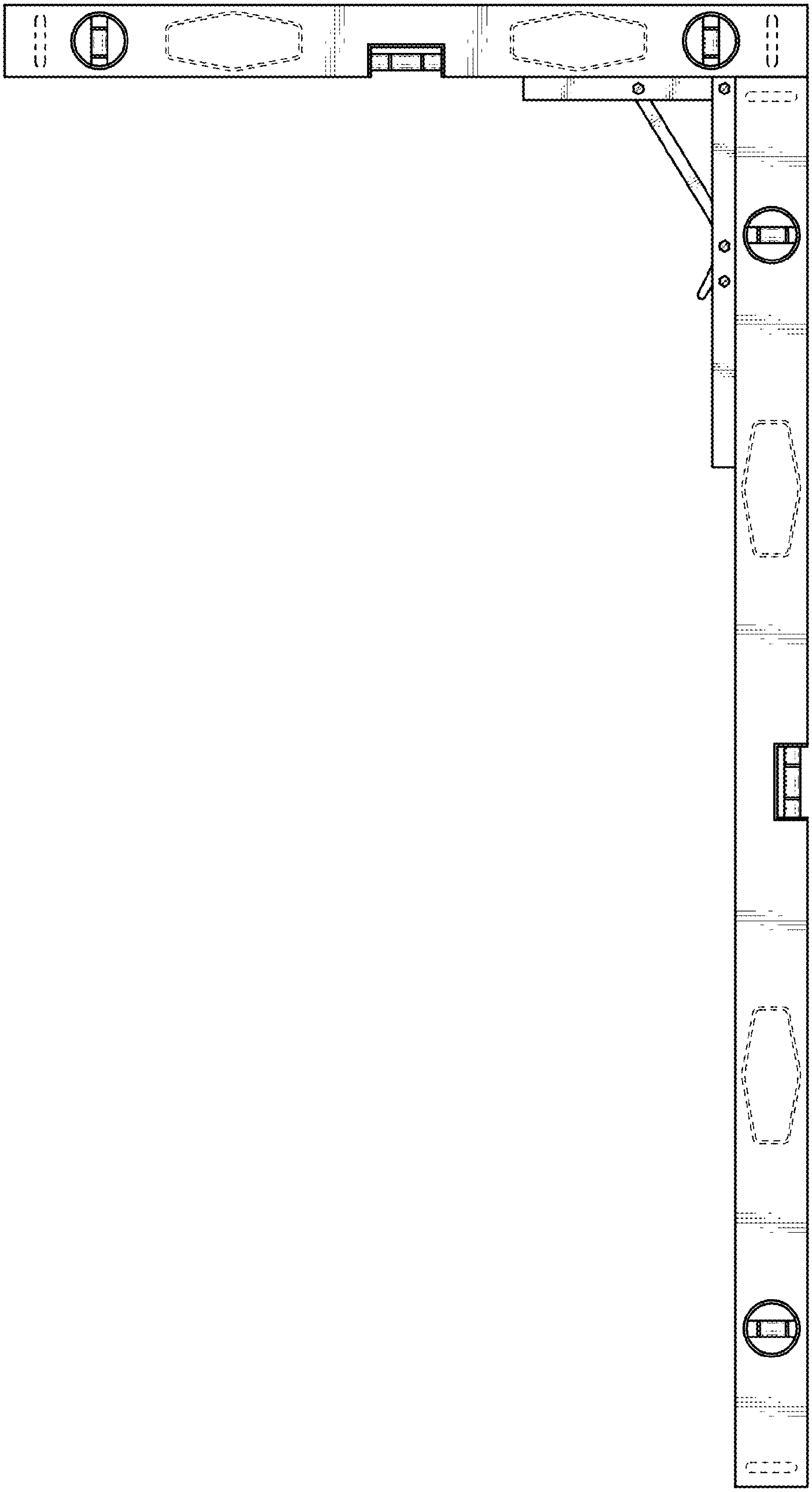


FIG. 3

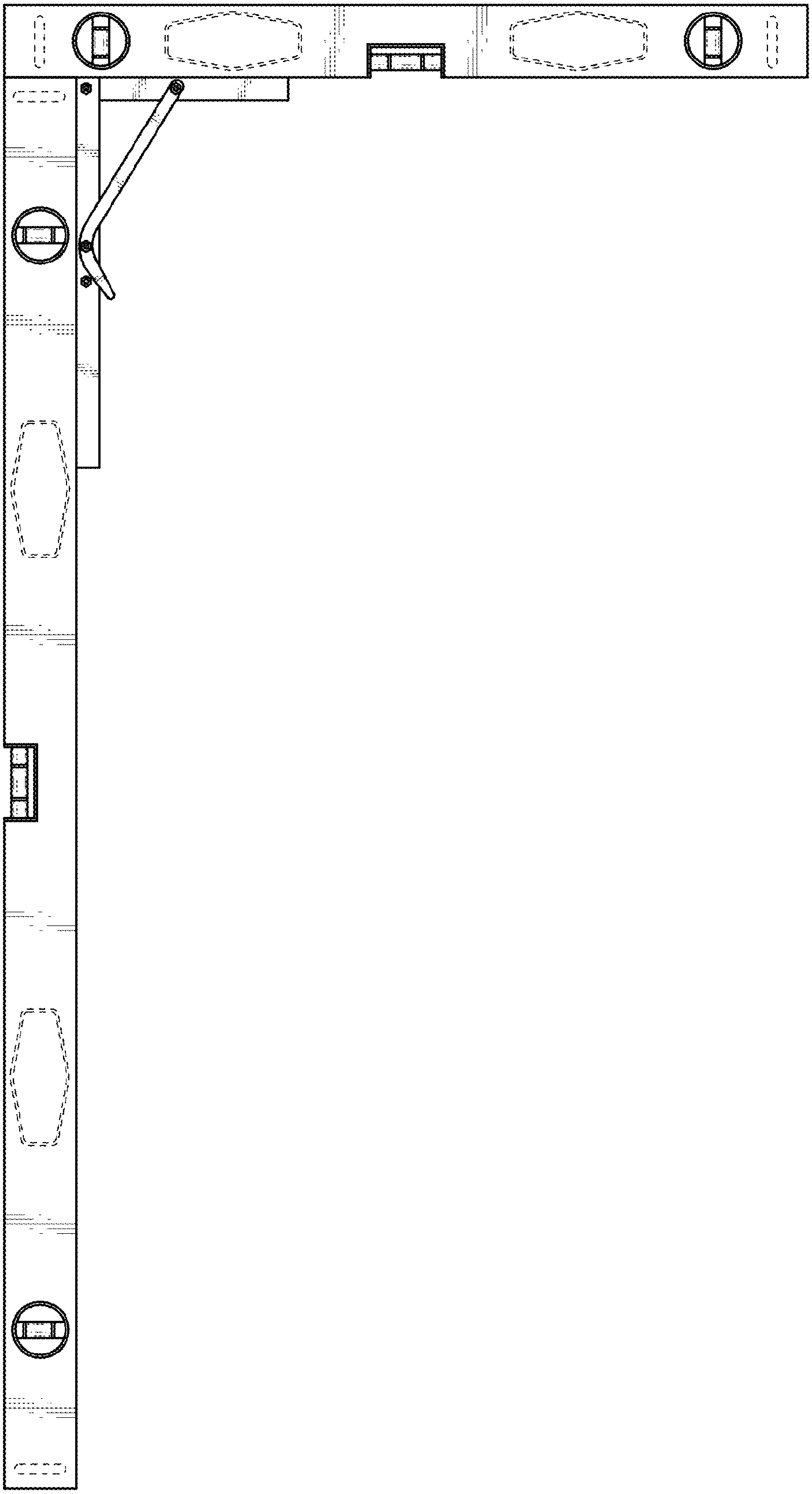


FIG. 4

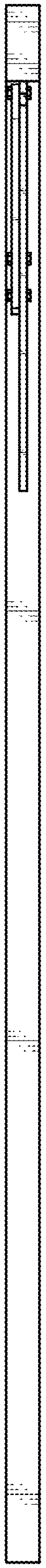


FIG. 5

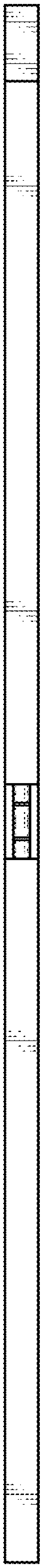


FIG. 6

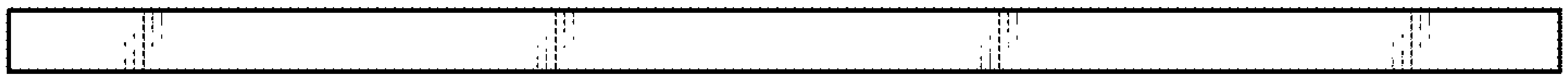


FIG. 7

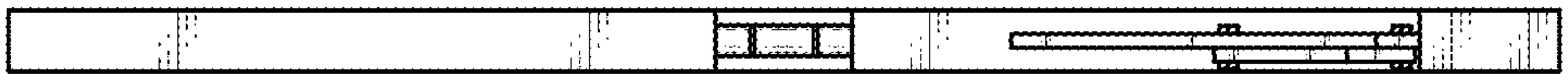


FIG. 8